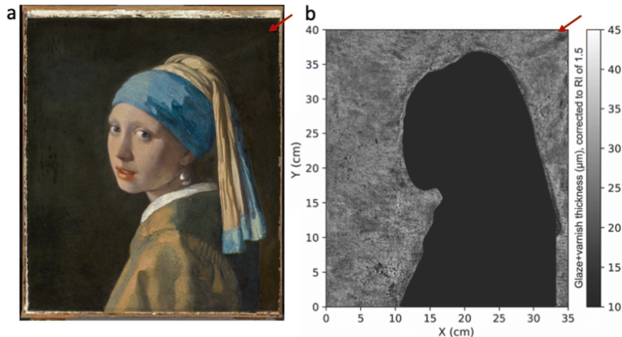


APPLICATION

OCT is a non-destructive, sub-surface, 3D imaging technique that can be used to assess the state of various forms of art, understand past conservation attempts, and plan future restoration efforts.



Vermeer's *Girl with a Pearl Earring*. (a) Polarized light photograph and (b) glaze and varnish layer thickness map extracted from OCT data.²*

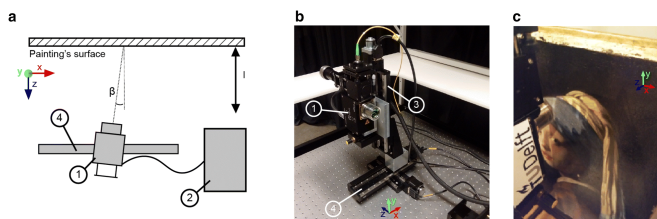
QUICK FACTS

- ◆ OCT is a non-destructive technique to image the layered or coated structure of various samples.
- ◆ OCT is well suited to examine the varnish and glaze layers of paintings; however, its penetration into paint is strongly dependent on the scattering properties.
- ◆ Cross Polarization can be used to reduce artifacts from strong surface reflections.
- ◆ The OCT scanner can be mounted on a gantry system to image small paintings as a whole² or particular areas of larger paintings.
- ◆ OCT has been used to examine cracks and bubbles in jade⁷, varnish and paint layers in ancient artifacts like Egyptian coffins⁸, and varnish on ceramics.

TYPICAL SETUP

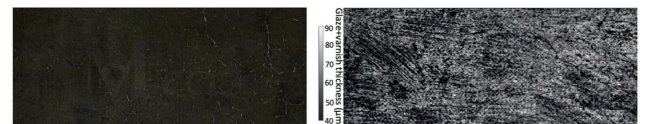
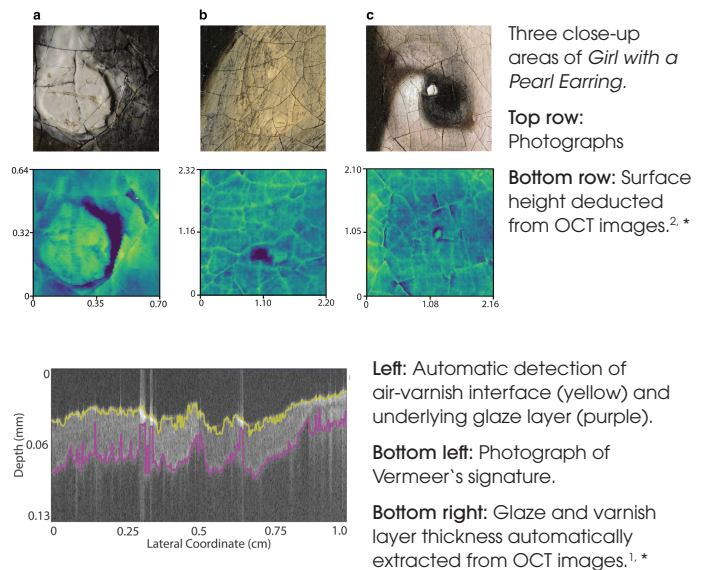
Smaller samples can be placed right under the scanner of the OCT system.

For imaging whole works of art, an automated control a gantry system can be employed²:



Automatic scanning of *Girl with a Pearl Earring*. (a) Sketch of setup, (b) photograph of scanner on gantry system, and (c) OCT system scanning the painting.^{2,*}

EXAMPLE IMAGES

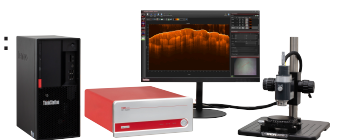


RECOMMENDED ITEMS

Choice of OCT System:

◆ GAN332C1 or GAN632C1:

- For Most Applications
- High-Resolution imaging at 880 nm



GAN632C1

◆ TEL221C1: For Ceramics

- Deeper Penetration into Material at 1300 nm

Useful Accessories:

- ◆ Thorlabs' OCTP series scanners are alternative scanners on Thorlabs' 30 mm cage system. These scanners can be adapted by the user, e.g. to accommodate beams of other imaging modalities or to implement cross polarization.

Interested? Email OCT@thorlabs.com for more information.

PUBLICATIONS

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- 2) W.S. Elkhuizen, T.W.J. Callewaert, E. Leonhardt, A. Vandivere, Y. Song, S.C. Pont, J.M.P. Geraedts, J. Dik, *Herit. Sci.*, **7**, 89, 2019
- 3) S. Kogou, A. Lucian, S. Bellesia, L. Burgio, K. Bailey, C. Brooks, H. Liang, *Appl. Phys. A*, **121** (3), 999, 2015
- 4) C.L. Koch Dandolo, M. Lopez, K. Fukunaga, Y. Ueno, R. Pillay, D. Giovannacci, Y.L. Du, X. Bai, M. Menu, V. Detalle, *Appl. Opt.*, **58** (5), 1281, 2019
- 5) T. Callewaert, J. Dik, J. Kalkman, *Opt. Express*, **25** (26), 32816, 2017
- 6) R. Tonga, M. Hu, X. Liua, Q. Zhang, H. Ge, T. Gang, X. Bai, C. Zuo, C. Bian, *Optik*, **199**, 163311, 2019
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